

What is claimed is:

1. High-frequency measuring system for measuring a device under test (19), comprising a measuring-device unit (2) and at least one high-frequency module (3, 24, 25), wherein each high-frequency module (3, 24, 25) can be placed spatially separately from the measuring-device unit (2) and each high-frequency module (3, 24, 25) can be connected to the measuring-device unit (2) via a digital interface (23, 26, 27),
characterised in that
the processing of input data to form a bitstream to be transmitted via the digital interface (26) takes place by assigning the symbols to states in the state diagram of the I-Q (in phase - quadrature phase) level in the measuring-device unit (2), and/or that a digitised intermediate-frequency signal is transmitted via the digital interface (27).
2. High-frequency measuring system according to claim 1,
characterised in that
the high-frequency module (3, 24, 25) comprises a transmitter device and/or a receiver device (28, 29) for communication with a device under test (19).
3. High-frequency measuring system according to claim 1 or 2,
characterised in that
the digital interface (23, 26, 27) is a serial interface.

4. High-frequency measuring system according to claim
1 or 2,
characterised in that
5 the digital interface (23, 26, 27) is a parallel
interface.
5. High-frequency measuring system according to any
one of claims 1 to 4,
10 **characterised in that**
the digital interface (23, 26, 27) is an optical
interface.
6. High-frequency measuring system according to any
15 one of claims 1 to 4,
characterised in that
the digital interface (23, 26, 27) is an electrical
interface.
- 20 7. High-frequency measuring system according to any
one of claims 1 to 6,
characterised in that
the at least one high-frequency module (3, 24, 25)
is supplied with electrical energy via a power-
25 supply unit (14, 40) independent from the
measuring-device unit (2).
8. High-frequency measuring system according to any
one of claims 1 to 7,
30 **characterised in that**
several identical ports (5.1, 5.2, 5.3) are
provided on the measuring-device unit (2) for the
digital interface (23).

9. High-frequency measuring system according to any
one of claims 1 to 8,
characterised in that
several different ports (5.1, 5.2, 5.3, 6.1, 6.2,
5 6.3) are provided on the measuring-device unit for
the digital interface (23).
10. High-frequency measuring system according to any
one of claims 1 to 9,
10 **characterised in that**
control data and/or user data can be transmitted in
a standardised form via the digital interface and
that the at least one high-frequency module (24')
comprises means for processing a high-frequency
15 signal with regard to the transmission of data in
standardised form via the digital interface and/or
for processing the data transmitted in standardised
form with regard to at least one given transmission
standard for the high-frequency signal.
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